

THYRISTORS

Also available to BS9341-F039

Silicon thyristors in metal envelopes, intended for use in general purpose three-phase power control circuits.

The series consists of reverse polarity types (anode to stud) identified by a suffix R: BTW92-800R to 1600R.

QUICK REFERENCE DATA

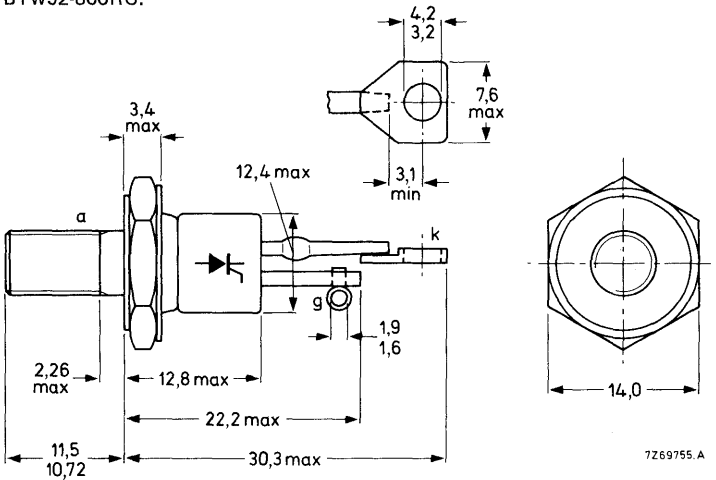
	V_{DRM}/V_{RRM}	BTW92-800R	1000R	1200R	1400R	1600R
		max.	800	1000	1200	1400
Repetitive peak voltages						V
Average on-state current			$I_{T(AV)}$		max.	20 A
R.M.S. on-state current			$I_{T(RMS)}$		max.	31 A
Non-repetitive peak on-state current			I_{TSM}		max.	400 A
Rate of rise of off-state voltage that will not trigger any device			dV_D/dt	<		300 V/ μ s
On request (see ordering note on page 4)			dV_D/dt	<		1000 V/ μ s

MECHANICAL DATA

Dimensions in mm

Fig. 1 TO-48: with metric M6 stud (ϕ 6 mm); e.g. BTW92-800R.

Types with $\frac{1}{4}$ in x 28 UNF stud (ϕ 6,35 mm) are available on request. These are indicated by the suffix U: BTW92-800RU.



Net mass: 14 g
 Diameter of clearance hole: max. 6,5 mm
 Accessories supplied on request: 56264A
 (mica washer, insulating ring, soldering tag)

Torque on nut: min. 1,7 Nm (17 kg cm)
 max. 3,5 Nm (35 kg cm)

Supplied with the device:
 1 nut, 1 lock washer
 Nut dimensions across the flats:
 M6: 10 mm
 $\frac{1}{4}$ in x 28 UNF: 11,1 mm

RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC 134)

Anode to cathode

		BTW92-800R	1000R	1200R	1400R	1600R
Non-repetitive peak voltages ($t \leq 10$ ms)	V_{DSM}/V_{RSM}	max. 800	1000	1200	1400	1600 V
Repetitive peak voltages	V_{DRM}/V_{RRM}	max. 800	1000	1200	1400	1600 V
Crest working voltages	V_{DWM}/V_{RWM}	max. 600	700	800	800	800 V *
Average on-state current (averaged over any 20 ms period) up to $T_{mb} = 85$ °C				$I_T(AV)$	max.	20 A
R.M.S. on-state current				$I_T(RMS)$	max.	31 A
Repetitive peak on-state current				I_{TRM}	max.	200 A
Non-repetitive peak on-state current; $t = 10$ ms; half sine-wave; $T_j = 125$ °C prior to surge; with reapplied V_{RWMmax}				I_{TSM}	max.	400 A
I^2t for fusing ($t = 10$ ms)				I^2t	max.	800 A ² s
Rate of rise of on-state current after triggering with $I_G = 500$ mA to $I_T = 60$ A				dI_T/dt	max.	300 A/ μ s
Rate of change of commutation current				see Fig. 9		

Gate to cathode

Reverse peak voltage		V_{RGM}	max.	10 V
Average power dissipation (averaged over any 20 ms period)		$P_G(AV)$	max.	1 W
Peak power dissipation		P_{GM}	max.	5 W

Temperatures

Storage temperature		T_{stg}	-55 to + 125 °C
Junction temperature		T_j	max. 125 °C

THERMAL RESISTANCE

From junction to mounting base	$R_{th j-mb}$	=	1 °C/W
From mounting base to heatsink	$R_{th mb-h}$	=	0,2 °C/W
Transient thermal impedance ($t = 1$ ms)	$Z_{th j-mb}$	=	0,06 °C/W

* To ensure thermal stability: $R_{th j-a} < 1,5$ °C/W (d.c. blocking) or < 3 °C/W (a.c.). For smaller heatsinks T_{jmax} should be derated. For a.c. see Fig. 3.

CHARACTERISTICS

Anode to cathode

On-state voltage $I_T = 50 \text{ A}; T_j = 25 \text{ }^\circ\text{C}$	V_T	<	2,3 V *
Rate of rise of off-state voltage that will not trigger any device; exponential method; $V_D = 2/3 V_{DRMmax}; T_j = 125 \text{ }^\circ\text{C}$	dV_D/dt	<	300 V/ μs
Reverse current $V_R = V_{RWMmax}; T_j = 125 \text{ }^\circ\text{C}$	I_R	<	5 mA
Off-state current $V_D = V_{DWMmax}; T_j = 125 \text{ }^\circ\text{C}$	I_D	<	5 mA
Latching current; $T_j = 25 \text{ }^\circ\text{C}$	I_L	<	200 mA
Holding current; $T_j = 25 \text{ }^\circ\text{C}$	I_H	<	200 mA

Gate to cathode

Voltage that will trigger all devices $V_D = 6 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$	V_{GT}	>	3,5 V
Voltage that will not trigger any device $V_D = V_{DRMmax}; T_j = 125 \text{ }^\circ\text{C}$	V_{GD}	<	200 mV
Current that will trigger all devices $V_D = 6 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$	I_{GT}	>	100 mA

Switching characteristics

Gate-controlled turn-on time ($t_{gt} = t_d + t_r$) when switched from $V_D = V_{DWMmax}$ to $I_T = 10 \text{ A}; I_{GT} = 150 \text{ mA}; dI_G/dt = 1 \text{ A}/\mu\text{s}; T_j = 25 \text{ }^\circ\text{C}$	t_{gt}	typ.	2 μs
	t_r	typ.	1,2 μs

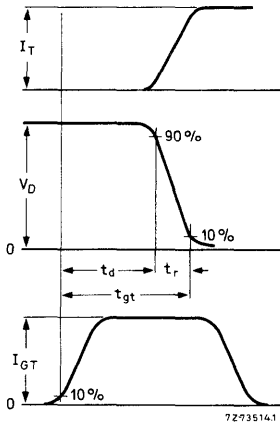


Fig. 2 Gate-controlled turn-on time definitions.

* Measured under pulse conditions to avoid excessive dissipation.

OPERATING NOTES

1. The terminals should neither be bent nor twisted; they should be soldered into the circuit so that there is no strain on them.
 During soldering the heat conduction to the junction should be kept to a minimum.

2. Switching losses in commutation.

For applications in which the thyristor is forced to switch from an on-state current I_{TRM} to a high reverse voltage at a high commutation rate ($-di_T/dt$), consult Fig. 9 (nomogram) to find the increase in total average power. This increase must be added to the loss from the curves in Fig. 3.

ORDERING NOTE

Types with dV_D/dt of $1000 \text{ V}/\mu\text{s}$ are available on request. Add suffix C to the type number when ordering; e.g. BTW92-800RC.

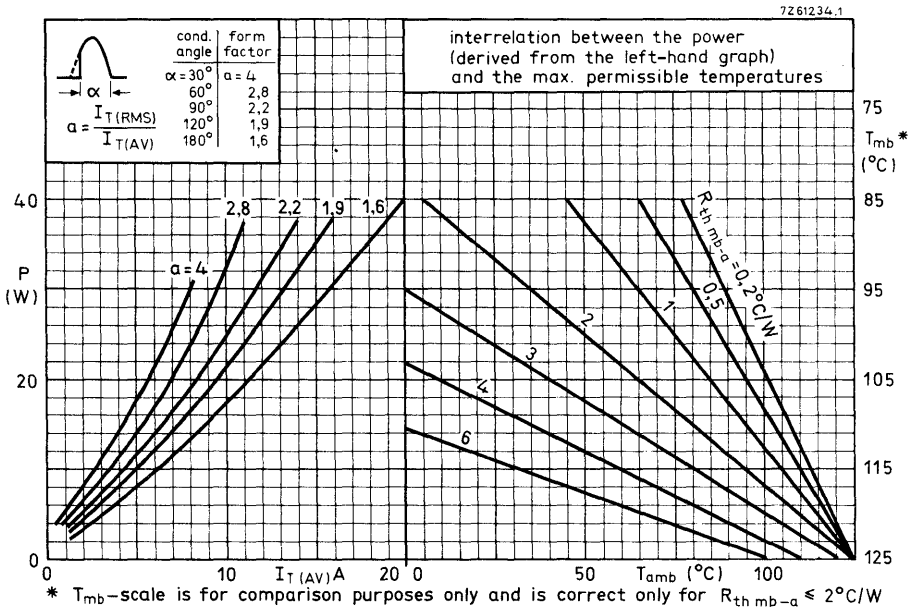


Fig. 3.

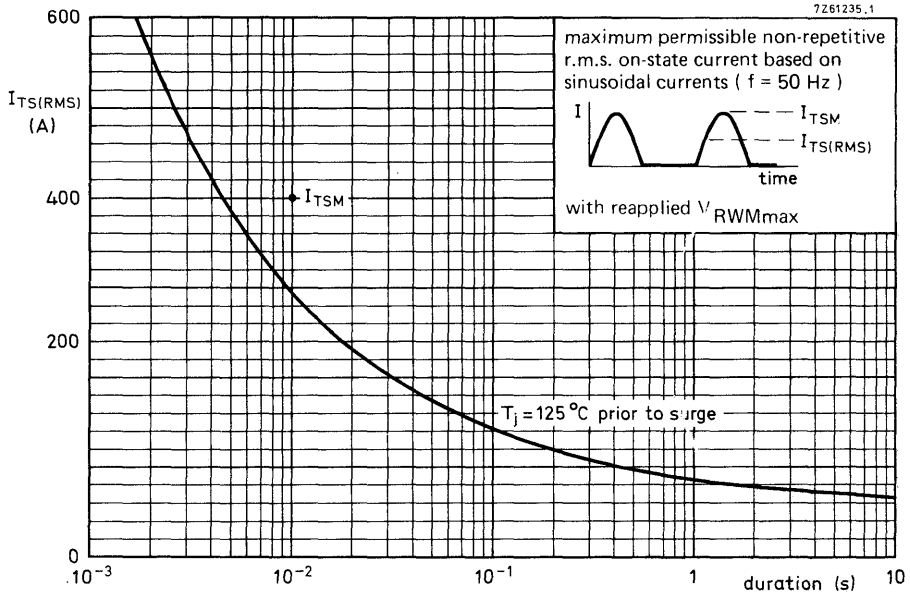


Fig. 4.

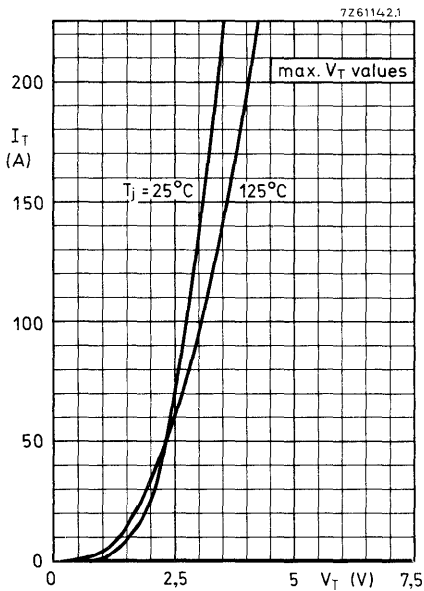


Fig. 5.

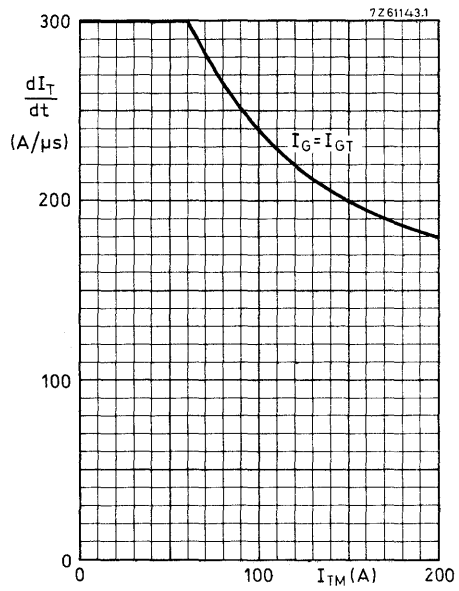


Fig. 6.

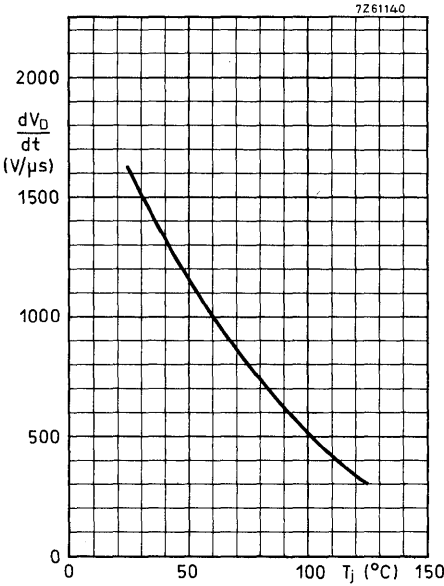


Fig. 7 Maximum rate of rise of off-state voltage that will not trigger any device (exponential method) as a function of T_j .

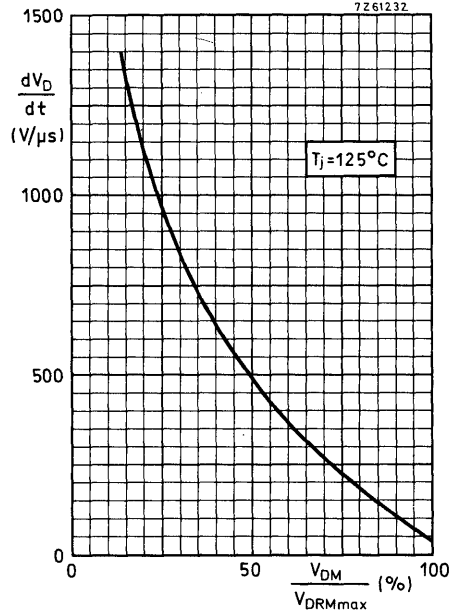


Fig. 8 Maximum rate of rise of off-state voltage that will not trigger any device (exponential method) as a function of applied voltage.

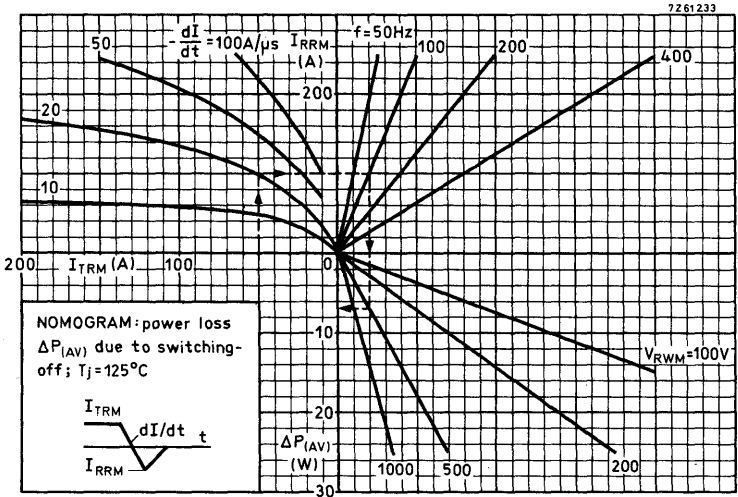


Fig. 9.

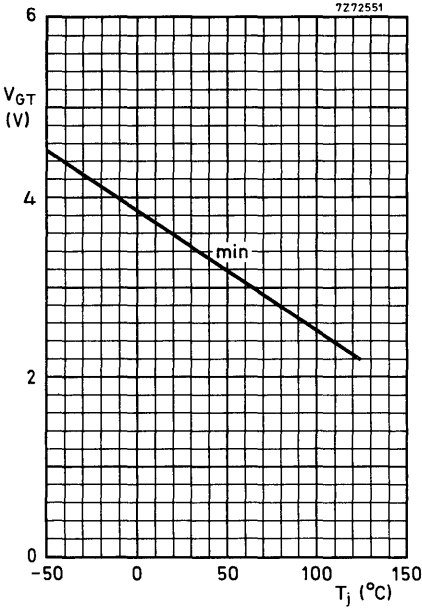


Fig. 10 Minimum gate voltage that will trigger all devices as a function of T_j .

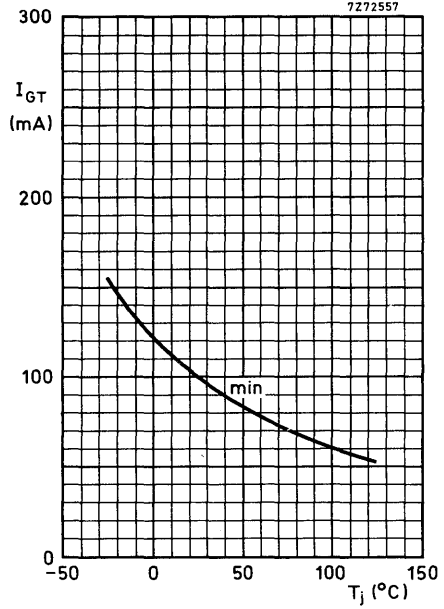


Fig. 11 Minimum gate current that will trigger all devices as a function of T_j .

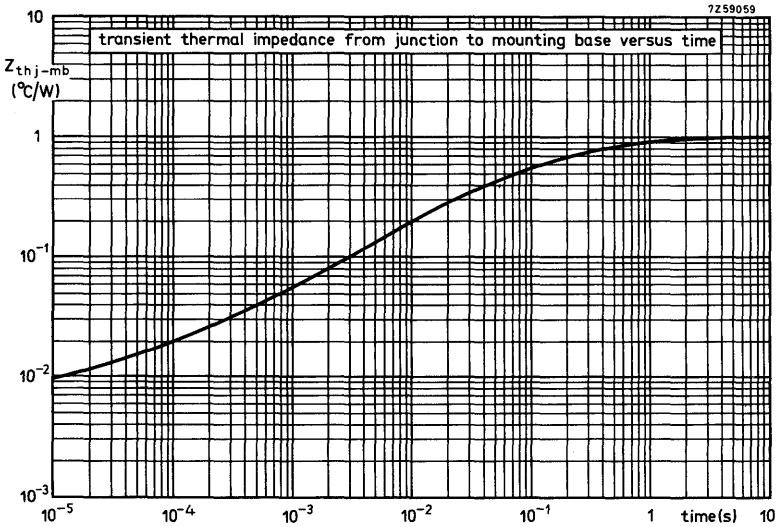


Fig. 12.

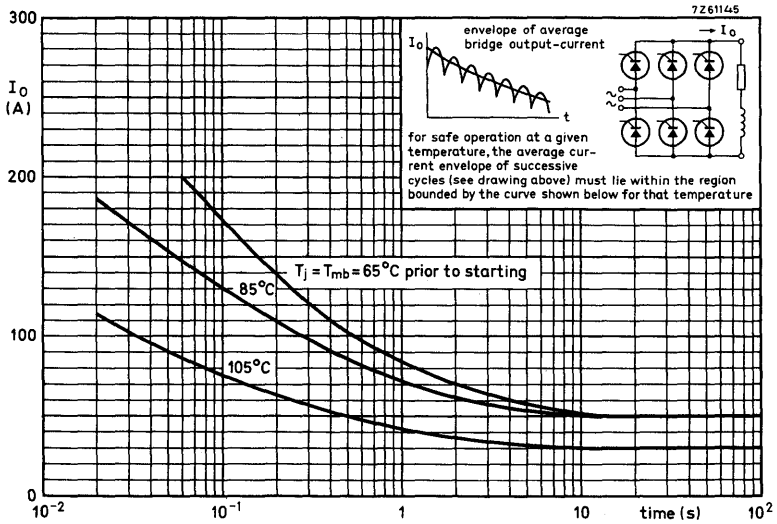
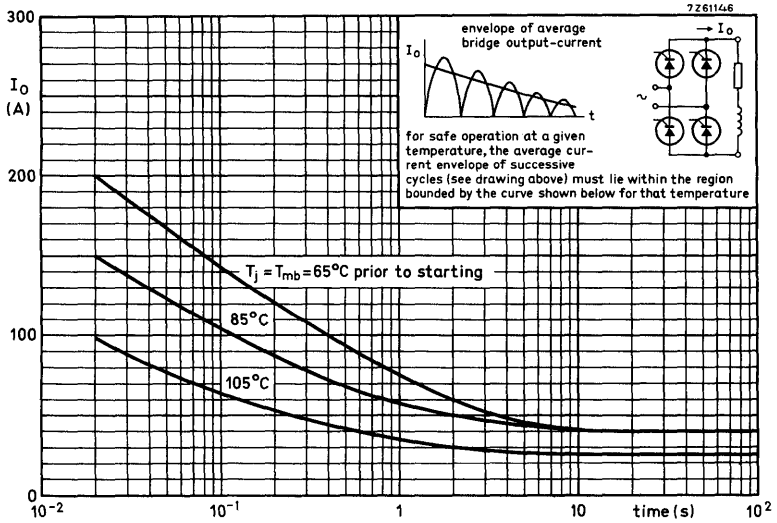


Fig. 13 Limits for starting or inrush currents.